Code: AP.PRE.REQ PTO/SB/33 (07-05) Approved for use through xx/xx/200x. OMB 0651-00xx U.S. Patent and Trademark Office, U.S. DEPARTMENT OF COMMERCE r the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number. **Docket Number (Optional)** PRE-APPEAL BRIEF REQUEST FOR REVIEW 8021-224 (SS-19575-US) I hereby certify that this correspondence is being deposited with the Application Number Filed United States Postal Service with sufficient postage as first class mail in an envelope addressed to "Mail Stop AF, Commissioner for 10/822,384 April 12, 2004 Patents, P.O. Box 1450, Alexandria, VA 22313-1450" [37 CFR 1.8(a)] December 11, 2007 First Named Inventor Jin Kook Jung Signature **Art Unit** Examiner Frank Chau Typed or printed Benjamin P. Sandvik 2826 name Applicant requests review of the final rejection in the above-identified application. No amendments are being filed with this request. This request is being filed with a notice of appeal. The review is requested for the reason(s) stated on the attached sheet(s). Note: No more than five (5) pages may be provided. I am the applicant/inventor. Signature assignee of record of the entire interest. Frank Chau See 37 CFR 3.71. Statement under 37 CFR 3.73(b) is enclosed. (Form PTO/SB/96) Typed or printed name 516-692-8888 attorney or agent of record. 34,136 Registration number Telephone number attorney or agent acting under 37 CFR 1.34. December 11, 2007 Registration number if acting under 37 CFR 1.34 NOTE: Signatures of all the inventors or assignees of record of the entire interest or their representative(s) are required.

This collection of information is required by 35 U.S.C. 132. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.11, 1.14 and 41.6. This collection is estimated to take 12 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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8021-224 (SS-19575-US)



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS:

Jung et al.

EXAMINER: Sandvik, Benjamin P

SERIAL NO.:

10/822,384

GROUP ART UNIT: 2826

FILED:

April 12, 2004

FOR:

SEMICONDUCTOR DEVICE AND METHOD OF LOCATING A

PREDETERMINED POINT ON THE SEMICONDUCTOR

DEVICE

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

PRE-APPEAL BRIEF REQUEST FOR REVIEW

Sir:

This paper is being filed with a Notice of Appeal Form (PTO/SB/31) and a Pre-Appeal Brief Request For Review Form (PTO/SB/33).

CERTIFICATE OF MAILING

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P.O. Box 1450, Alexandria, VA 22313-1450 on December 11, 2007.	

Dated:

Frank Cha

REMARKS

Please consider the following reasons for this Pre-Appeal Brief Request For Review.

Claims 1-4, 23 and 24 are pending and stand rejected in the above-referenced application.

Claims 1-4, 23 and 24 stand rejected under 35 U.S.C. § 102(e) as being anticipated by Wang et al (U.S. Pub. 2002/0175419). However, there are clear errors in Examiner's rejections based on Wang.

Claim 1 recites, *inter alia*, a number of dummy patterns substantially greater than a number of marking patterns. For example, in the present disclosure, the number of dummy patterns (110) is substantially greater than the number of marking patterns (115). See e.g., Fig. 4 of the present disclosure.

In the October 11, 2007 Final Office Action, the Examiner states that Wang teaches dummy patterns (700) and marking patterns (1200) wherein a number of the dummy patterns (700) is substantially greater than a number of the marking patterns (1200). See October 11, 2007 Final Office Action, Page 2. In stark contrast to the Examiner's assertion, elements (1200) are not marking patterns, but vias. The vias form plugs when filled with metal layer. See e.g., paragraph [0075] of Wang. As such, the vias (1200) cannot be used as marking patterns used for counting the dummy patterns.

Furthermore, even assuming, *arguendo*, that elements (1200) can be marking patterns, Wang does not disclose that a number of the dummy patterns (700) is substantially greater than a number of the marking patterns because if the vias (1200)

in Fig. 12B can be marking patterns, other vias (600) in Fig. 12B can also be marking patterns. Then, in contrast to the Examiner's assertion, in Wang, a number of marking patterns (1200) is greater than a number of patterns (700). See e.g., Fig. 12B of Wang.

Claim 23 recites, *inter alia*, marking patterns surrounding at least a group of dummy patterns. For example, in the present disclosure, marking patterns (215) surround at least a group of dummy patterns (210). <u>See e.g.</u>, Fig. 5 of the present disclosure.

In the October 11, 2007 Final Office Action, the Examiner states that Wang teaches dummy patterns (1200) and marking patterns (700). See October 11, 2007 Final Office Action, Page 3. In stark contrast to the Examiner's assertion, elements (1200) are not dummy patterns for a CMP method formed in a uniform pattern over the semiconductor substrate. As discussed above, the elements (1200) are vias. Furthermore, even assuming, arguendo, that the elements (1200) can be dummy patterns, the patterns (700) do not surround a group of the dummy patterns. In contrast, only a single via (1200) is surrounded by the patterns (700). See e.g., Fig. 12B of Wang.

Claim 24 recites, *inter alia*, marking patterns and the predetermined plural numbers of the dummy patterns grouped by the marking patterns form a unit, which is repeated. As stated above, elements (1200) are vias, not marking patterns.

Therefore, there are clear errors in Examiner's rejections based on Wang.

An early and favorable reconsideration is earnestly solicited.

Respectfully submitted,

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